

**4M BIT DYNAMIC RAM**  
**(FAST PAGE MODE)**

**DESCRIPTION**

The NEC μPD424800-L is a 524288-word by 8 bits dynamic CMOS RAM with optional fast page mode. CMOS sense amplifier, peripheral circuits and 1 transistor memory cell technique realize high speed access, cycle time and low power dissipation. Refresh is accomplished by performing  $\overline{RAS}$  only refresh cycles, hidden refresh cycles,  $\overline{CAS}$  before  $\overline{RAS}$  refresh cycles, or normal read or write cycles on the 1024 address combinations of A<sub>0</sub> to A<sub>9</sub>, during a 128 ms period.

The μPD424800-L is packaged in 28-pin plastic SOJ, 28-pin plastic ZIP and 28-pin plastic TSOP. ★

**FEATURES**

- 524288 words by 8 bits organization

DEVICE	ACCESS TIME (MAX.)	R/W CYCLE (MIN.)	PAGE MODE CYCLE (MIN.)
μPD424800-70L	70 ns	140 ns	45 ns
μPD424800-80L	80 ns	160 ns	50 ns
μPD424800-10L	100 ns	190 ns	60 ns

- Low power dissipation
  - Active . . . . . 577.5 mW MAX. (μPD424800-70L)
  - 522.5 mW MAX. (μPD424800-80L)
  - 440.0 mW MAX. (μPD424800-10L)
  - Standby . . . . . 1.1 mW MAX. (CMOS level)
- Single +5V ± 10% power supply
- On-chip substrate bias generator
- Multiplexed address inputs . . . . . Row Address: A<sub>0</sub> to A<sub>9</sub>, Column Address: A<sub>0</sub> to A<sub>8</sub>
- Non latched I/O, TTL-compatible
- Read-modify-write, Fast Page Mode capability
- 1024 refresh cycles/128 ms
- $\overline{RAS}$  only refresh, hidden refresh and  $\overline{CAS}$  before  $\overline{RAS}$  internal address refresh

The information in this document is subject to change without notice.

The mark ★ shows revised points.

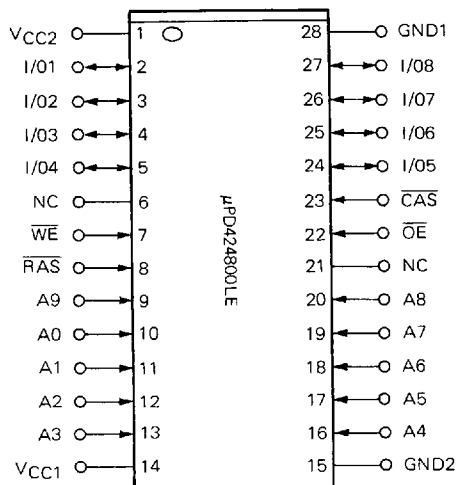
## ORDERING INFORMATION\*

PART NUMBER	PACKAGE	ACCESS TIME (MAX.)	QUALITY GRADE
$\mu$ PD424800LE-70L	28-Pin Plastic SOJ	70 ns	Standard
$\mu$ PD424800LE-80L	28-Pin Plastic SOJ	80 ns	Standard
$\mu$ PD424800LE-10L	28-Pin Plastic SOJ	100 ns	Standard
$\mu$ PD424800V-70L	28-Pin Plastic ZIP	70 ns	Standard
$\mu$ PD424800V-80L	28-Pin Plastic ZIP	80 ns	Standard
$\mu$ PD424800V-10L	28-Pin Plastic ZIP	100 ns	Standard
$\mu$ PD424800G5-70L-7JD	28-Pin Plastic TSOP	70 ns	Standard
$\mu$ PD424800G5-80L-7JD	28-Pin Plastic TSOP	80 ns	Standard
$\mu$ PD424800G5-10L-7JD	28-Pin Plastic TSOP	100 ns	Standard
$\mu$ PD424800G5-70L-7KD	28-Pin Plastic TSOP(Reverse bent)	70 ns	Standard
$\mu$ PD424800G5-80L-7KD	28-Pin Plastic TSOP(Reverse bent)	80 ns	Standard
$\mu$ PD424800G5-10L-7KD	28-Pin Plastic TSOP(Reverse bent)	100 ns	Standard

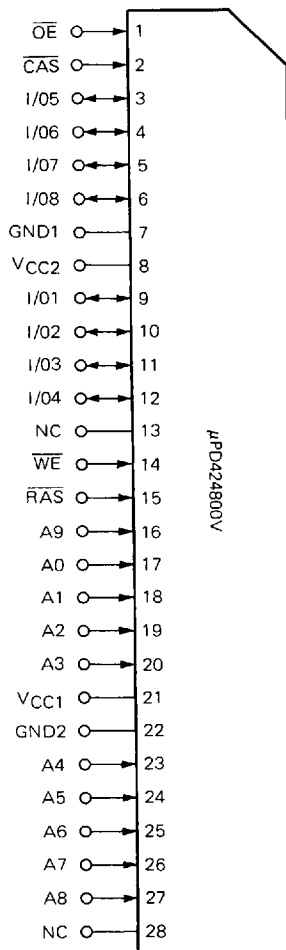
Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

PIN CONFIGURATION★

28-pin Plastic SOJ  
(Top View)

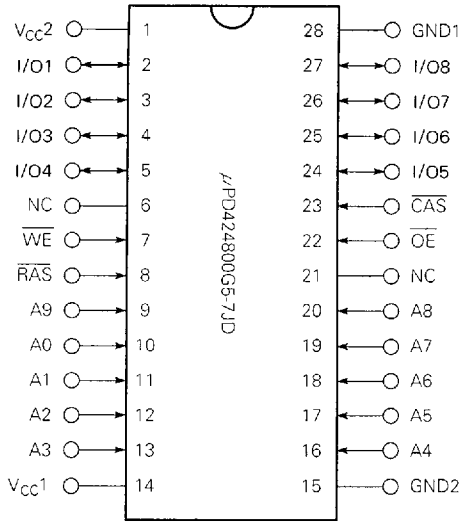


28-pin Plastic ZIP  
(Front View)

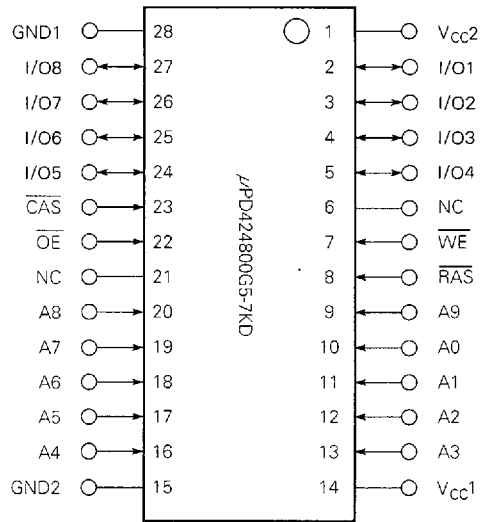


- A0 to A9      Addresses Inputs
- I/01 to I/08      Data Inputs/Outputs
- RAS      Row Address Strobe
- CAS      Column Address Strobe
- WE      Write Enable
- OE      Output Enable
- VCC1, 2      Supply Voltage
- GND1, 2      Ground
- NC      No Connection

28-Pin Plastic TSOP  
(Top View)



28-Pin Plastic TSOP(Reverse bent)  
(Top View)



- |                         |                       |
|-------------------------|-----------------------|
| A0 to A9                | Addresses Inputs      |
| I/O1 to I/O8            | Data Inputs/Outputs   |
| $\overline{\text{RAS}}$ | Row Address Strobe    |
| $\overline{\text{CAS}}$ | Column Address Strobe |
| $\overline{\text{WE}}$  | Write Enable          |
| $\overline{\text{OE}}$  | Output Enable         |
| VCC1, 2                 | Supply Voltage        |
| GND1, 2                 | Ground                |
| NC                      | No Connection         |

**ELECTRICAL SPECIFICATIONS**

**ABSOLUTE MAXIMUM RATINGS\***

Voltage on Any Pin Relative to GND	$V_T$	-1.0 to +7.0 V
Supply Voltage	$V_{CC}$	-1.0 to +7.0 V
Short Circuit Output Current	$I_o$	50 mA
Power Dissipation	$P_D$	1 W
Operating Temperature	$T_{opt}$	0 to +70 °C
Storage Temperature	$T_{stg}$	-55 to +125 °C

\*COMMENT: Exposing the device to stress above those listed in Absolute Maximum Ratings could cause permanent damage. The device is not meant to be operated under conditions outside the limits described in the operational section of this specification. Exposure to Absolute Maximum Rating conditions for extended periods may affect device reliability.

**RECOMMENDED OPERATING CONDITIONS** Notes 1, 2

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP	MAX.	UNIT
Supply Voltage	$V_{CC}$		4.5	5.0	5.5	V
High Level Input Voltage	$V_{IH}$		2.4		$V_{CC}+1.0$	V
Low Level Input Voltage	$V_{IL}$		-1.0		0.8	V
Ambient Temperature	$T_a$		0		70	°C

**DC CHARACTERISTICS (Recommended Operating Conditions unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP	MAX	UNIT	NOTE
Operating Current	$I_{CC1}$	$\overline{RAS}, \overline{CAS}$ Cycling			105	mA	3
		$t_{RC}=t_{RC(MIN.)}, I_O=0$ mA	μPD424800-70L		95		
			μPD424800-80L		80		
Standby Current	$I_{CC2}$	$\overline{RAS}, \overline{CAS} \geq V_{IH(MIN.)}, I_O=0$ mA			2	mA	
		$\overline{RAS}, \overline{CAS} \geq V_{CC}-0.2$ V, $I_O=0$ mA			0.2		
Refresh Current	$I_{CC3}$	$\overline{RAS}$ Cycling,	μPD424800-70L		105	mA	3
		$\overline{CAS} \geq V_{IH(MIN.)}$	μPD424800-80L		95		
		$t_{RC}=t_{RC(MIN.)}, I_O=0$ mA	μPD424800-10L		80		
Operating Current (Page Mode)	$I_{CC4}$	$\overline{RAS} \leq V_{IL(MAX.)}$ ,	μPD424800-70L		80	mA	3
		$\overline{CAS}$ Cycling	μPD424800-80L		70		
		$t_{PC}=t_{PC(MIN.)}, I_O=0$ mA	μPD424800-10L		60		
Refresh Current ( $\overline{CAS}$ before $\overline{RAS}$ Refresh)	$I_{CC5}$	$\overline{RAS}$ Cycling,	μPD424800-70L		105	mA	3
		$t_{RC}=t_{RC(MIN.)}, I_O=0$ mA	μPD424800-80L		95		
			μPD424800-10L		80		
Battery Back up current (Standby with $\overline{CAS}$ Before $\overline{RAS}$ Refresh)	$I_{CC6}$	Stand-by: $V_{CC}-0.2V \leq \overline{RAS}$ $\overline{CAS} \leq V_{IH} MAX.$ $\overline{CAS}$ Before $\overline{RAS}$ Refresh: $t_{RAS} \leq 200ns$ 1024 cycle/128ms $\overline{OE}=V_{IH}$ A0-A9, $\overline{WE}=V_{IH}$ OR $V_{IL}$ else input: $V_{CC}-0.2V \leq V_{IH} \leq V_{IH} MAX.$ $0V \leq V_{IL} \leq 0.2V$ output: Hi-z			300	μA	
Input Leakage Current	$I_{I(L)}$	$V_I=0$ to 5.5 V all other pins not under test=0 V	-10		10	μA	
Output Leakage Current	$I_{O(L)}$	$D_{OUT}$ is disabled $V_O=0$ to 5.5 V	-10		10	μA	
Output High Voltage	$V_{OH}$	$I_O=5$ mA	2.4			V	
Output Low Voltage	$V_{OL}$	$I_O=4.2$ mA			0.4	V	

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## CAPACITANCE (Ta=25°C, f=1 MHz)

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Input Capacitance	C <sub>I1</sub>	A0 to A9			5	pF
	C <sub>I2</sub>	RAS, CAS, $\overline{WE}$ , $\overline{OE}$			7	pF
Data Input/Output Capacitance	C <sub>D</sub>	I/01 to I/08			7	pF

AC CHARACTERISTICS (Recommended Operating Conditions unless Otherwise Noted) Notes 2, 4, 5

PARAMETER	SYMBOL	μPD424800-70L		μPD424800-80L		μPD424800-10L		UNIT	NOTE
		MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
Random Read or Write Cycle Time	t <sub>RC</sub>	140		160		190		ns	6
Read Write Cycle Time	t <sub>RWC</sub>	185		210		250		ns	6
Fast Page Mode Cycle Time (Read or Write)	t <sub>PC</sub>	45		50		60		ns	6
Fast Page Mode Cycle Time (Read Modify Write)	t <sub>PRWC</sub>	90		100		120		ns	6
Access Time from $\overline{\text{RAS}}$	t <sub>RAC</sub>		70		80		100	ns	4,5,7
Access Time from $\overline{\text{CAS}}$	t <sub>CAC</sub>		20		20		25	ns	4,5,7
Access Time from Column Address	t <sub>AA</sub>		35		40		50	ns	4,5,7
Access Time from $\overline{\text{CAS}}$ Precharge	t <sub>ACP</sub>		40		45		55	ns	4,5,7
Access Time from $\overline{\text{OE}}$	t <sub>OE A</sub>		20		20		25	ns	4,5,7
$\overline{\text{RAS}}$ to Column Address Delay Time	t <sub>RAD</sub>	15	35	17	40	17	50	ns	7
$\overline{\text{CAS}}$ → Data Setup Time	t <sub>CLZ</sub>	0		0		0		ns	
$\overline{\text{OE}}$ → Data Setup Time	t <sub>OLZ</sub>	0		0		0		ns	
Output Buffer Turn-off Delay (CAS)	t <sub>OFF</sub>	0	15	0	15	0	20	ns	8
OE Data Delay Time	t <sub>OED</sub>	15		15		20		ns	
Output Buffer Turn-off Delay ( $\overline{\text{OE}}$ )	t <sub>OEZ</sub>	0	15	0	15	0	20	ns	8
$\overline{\text{OE}}$ Command Hold Time	t <sub>OE H</sub>	0		0		0		ns	
$\overline{\text{OE}}$ to $\overline{\text{RAS}}$ inactive Setup Time	t <sub>OES</sub>	0		0		0		ns	
Transition time (rise and fall)	t <sub>T</sub>	3	50	3	50	3	50	ns	
$\overline{\text{RAS}}$ Precharge time	t <sub>RP</sub>	60		70		80		ns	
$\overline{\text{RAS}}$ Pulse Width (Random Read, Write)	t <sub>RAS</sub>	70	10000	80	10000	100	10000	ns	
$\overline{\text{RAS}}$ Pulse Width (Fast Page Mode)	t <sub>RASP</sub>	70	125000	80	125000	100	125000	ns	
$\overline{\text{RAS}}$ Hold Time	t <sub>RSH</sub>	20		20		25		ns	
$\overline{\text{RAS}}$ Hold Time from $\overline{\text{CAS}}$ Precharge	t <sub>RHCP</sub>	40		45		55		ns	
$\overline{\text{CAS}}$ Pulse Width	t <sub>CAS</sub>	20	10000	20	10000	25	10000	ns	
$\overline{\text{CAS}}$ Hold Time	t <sub>CSH</sub>	70		80		100		ns	
$\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ Delay Time	t <sub>RCD</sub>	20	50	25	60	25	75	ns	7
$\overline{\text{CAS}}$ to $\overline{\text{RAS}}$ Precharge Time	t <sub>CRP</sub>	5		5		5		ns	
$\overline{\text{CAS}}$ Precharge Time	t <sub>CPN</sub>	10		10		10		ns	
$\overline{\text{CAS}}$ Precharge Time (Fast Page Mode)	t <sub>CP</sub>	10		10		10		ns	
$\overline{\text{RAS}}$ Precharge $\overline{\text{CAS}}$ Hold Time	t <sub>RPC</sub>	5		5		5		ns	
Row Address Setup Time	t <sub>ASR</sub>	0		0		0		ns	
Row Address Hold Time	t <sub>RAH</sub>	10		12		12		ns	
Column Address Setup Time	t <sub>ASC</sub>	0		0		0		ns	
Column Address Hold Time	t <sub>CAH</sub>	15		15		20		ns	
Column Address Lead Time Referenced to $\overline{\text{RAS}}$	t <sub>RAL</sub>	35		40		50		ns	
Read Command Setup Time	t <sub>RCS</sub>	0		0		0		ns	
Read Command Hold Time Referenced to $\overline{\text{RAS}}$	t <sub>RRH</sub>	0		0		0		ns	9
Read Command Hold Time Referenced to $\overline{\text{CAS}}$	t <sub>RCH</sub>	0		0		0		ns	9
Write Command Hold Time Referenced to $\overline{\text{CAS}}$	t <sub>WCH</sub>	10		15		20		ns	10
Write Command Pulse Width	t <sub>WP</sub>			15		20		ns	10
Data-in Setup Time	t <sub>DS</sub>	0		0		0		ns	11
Data-in Hold Time	t <sub>DH</sub>	15		15		20		ns	11
Write Command Setup Time	t <sub>WCS</sub>	0		0		0		ns	
$\overline{\text{RAS}}$ to $\overline{\text{WE}}$ Delay Time	t <sub>RWD</sub>	90		105		130		ns	12
$\overline{\text{CAS}}$ to $\overline{\text{WE}}$ Delay Time	t <sub>CWD</sub>	40		45		55		ns	12
Column Address to $\overline{\text{WE}}$ Delay Time	t <sub>AWD</sub>	55		65		80		ns	12
Write Command to $\overline{\text{RAS}}$ Lead Time	t <sub>RWL</sub>	20		20		25		ns	

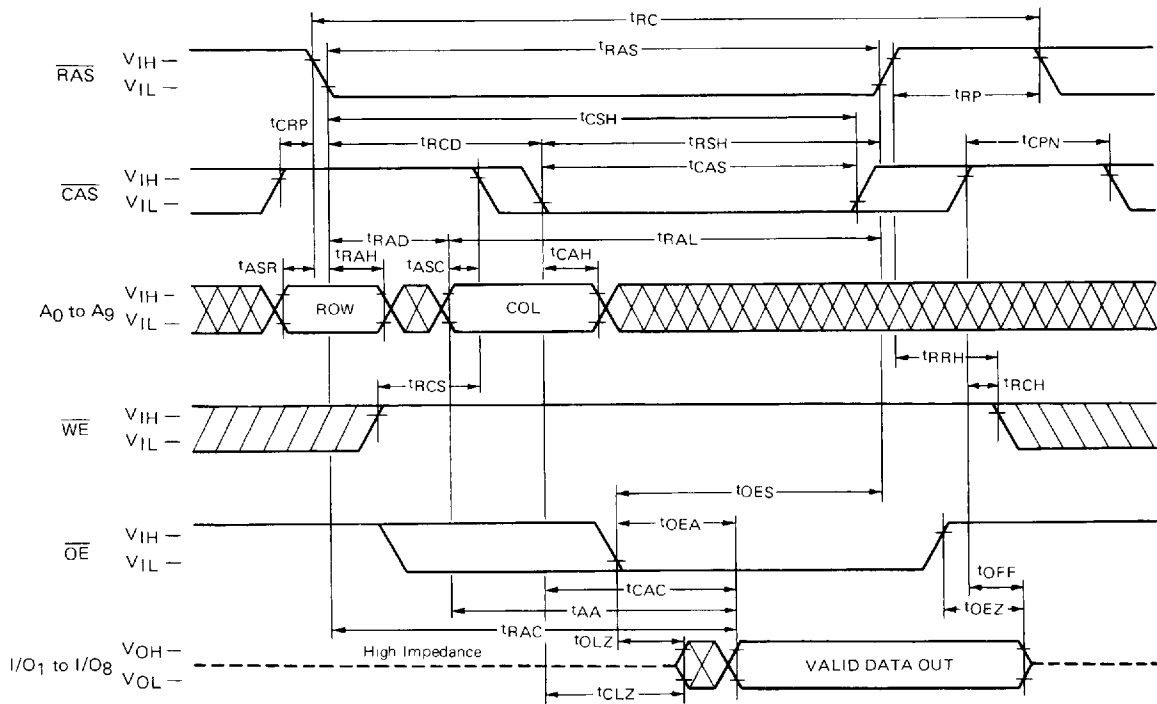
PARAMETER	SYMBOL	μPD424800-70L		μPD424800-80L		μPD424800-10L		UNIT	NOTE
		MIN	MAX	MIN	MAX	MIN	MAX.		
Write Command to $\overline{\text{CAS}}$ Lead Time	tCWL	15		15		20		ns	
$\overline{\text{CAS}}$ Setup Time for CBR Refresh	tCSR	5		5		5		ns	
$\overline{\text{CAS}}$ Hold Time for CBR Refresh	tCHR	15		15		20		ns	
Refresh Period	tREF		128		128		128	ms	

**NOTE**

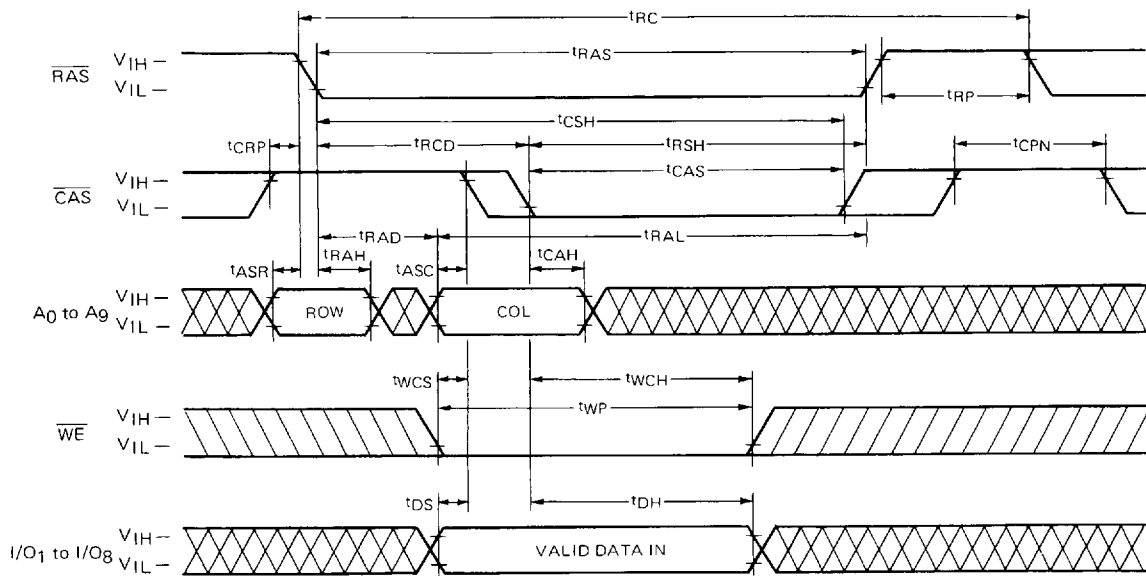
- (1) All voltages referenced to GND
- (2) An initial pause of 100 μs is required after power-on followed by 8 refresh ( $\overline{\text{RAS}}$  only refresh or  $\overline{\text{CAS}}$  before  $\overline{\text{RAS}}$  refresh) cycles before proper device operation is achieved.
- (3) I<sub>CC1</sub>, I<sub>CC3</sub>, I<sub>CC4</sub> and I<sub>CC5</sub> depend on output loading and cycle rates. Specified values are obtained with the output open. In addition to this, I<sub>CC3</sub> is measured on condition that Column addresses in  $\overline{\text{RAS}}$  only cycle are held high or Low level and I<sub>CC4</sub> is measured on condition that column addresses are charged only one time during t<sub>PC</sub> (MIN.).
- (4) AC measurements assume t<sub>T</sub>=5 ns
- (5) V<sub>IH</sub>(MIN) and V<sub>IL</sub>(MAX.) are reference levels for measuring timing of input signals.  
Transition times are measured between V<sub>IH</sub> and V<sub>IL</sub>  
Access times are measured at V<sub>OH</sub>(MIN.) and V<sub>OL</sub>(MAX) and loading condition is 2TTL + 100 pF
- (6) The minimum specifications are used only to indicate cycle time at which proper operation over the full temperature range (T<sub>a</sub>=0 to 70° C) is assured.
- (7) If t<sub>RCD</sub> ≤ t<sub>RCD</sub>(MAX) and t<sub>RAD</sub> ≤ t<sub>RAD</sub>(MAX), access time is defined by t<sub>RAC</sub>(MAX.)  
If t<sub>RCD</sub> ≥ t<sub>RCD</sub>(MAX), access time is defined by t<sub>CAC</sub>(MAX) and if t<sub>RAD</sub> ≥ t<sub>RAD</sub>(MAX), access time is defined by t<sub>AA</sub>(MAX.)
- (8) t<sub>OFF</sub>(MAX) defines the time at which the output achieves the open circuit condition and is not referenced to V<sub>OH</sub> or V<sub>OL</sub>
- (9) Either t<sub>RRH</sub> or t<sub>RCH</sub> must be satisfied for a read cycle
- (10) t<sub>WP</sub> is applicable for late write cycle or read-modify-write cycle. In early write cycle, t<sub>WCH</sub>(MIN.) should be satisfied.
- (11) These parameters are referenced to  $\overline{\text{CAS}}$  leading edge in early write cycles and to  $\overline{\text{WE}}$  leading edge in late write or read-modify-write cycles.
- (12) These parameters are the condition defining read-modify-write cycle.



READ CYCLE

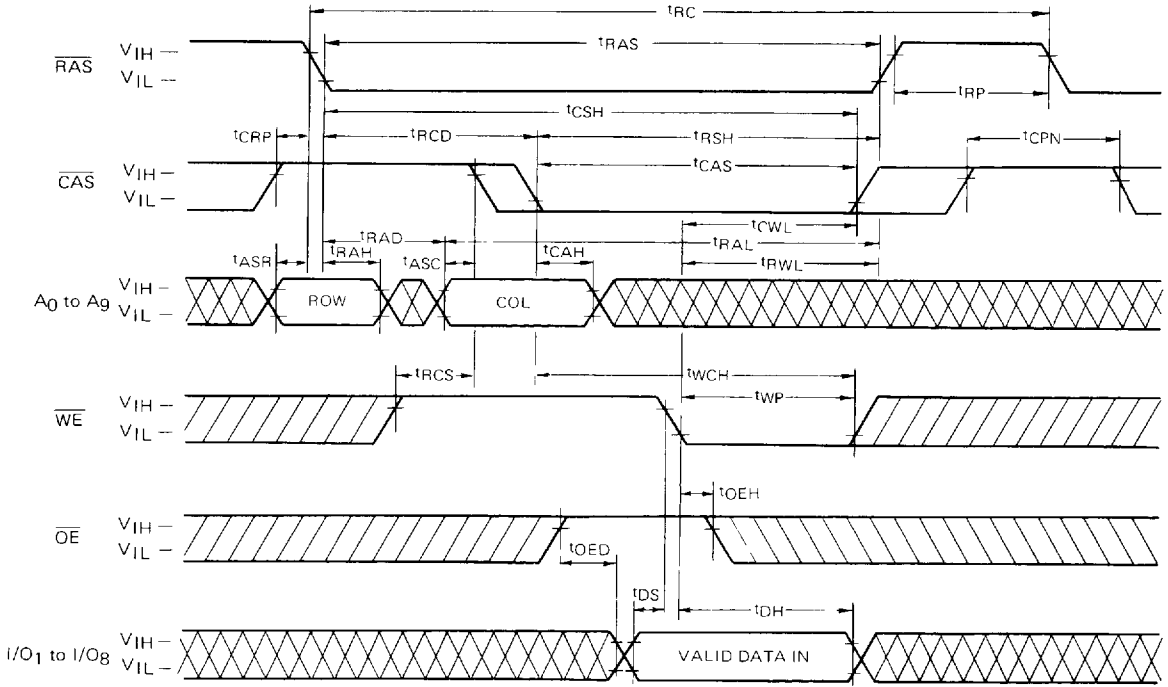


EARLY WRITE CYCLE

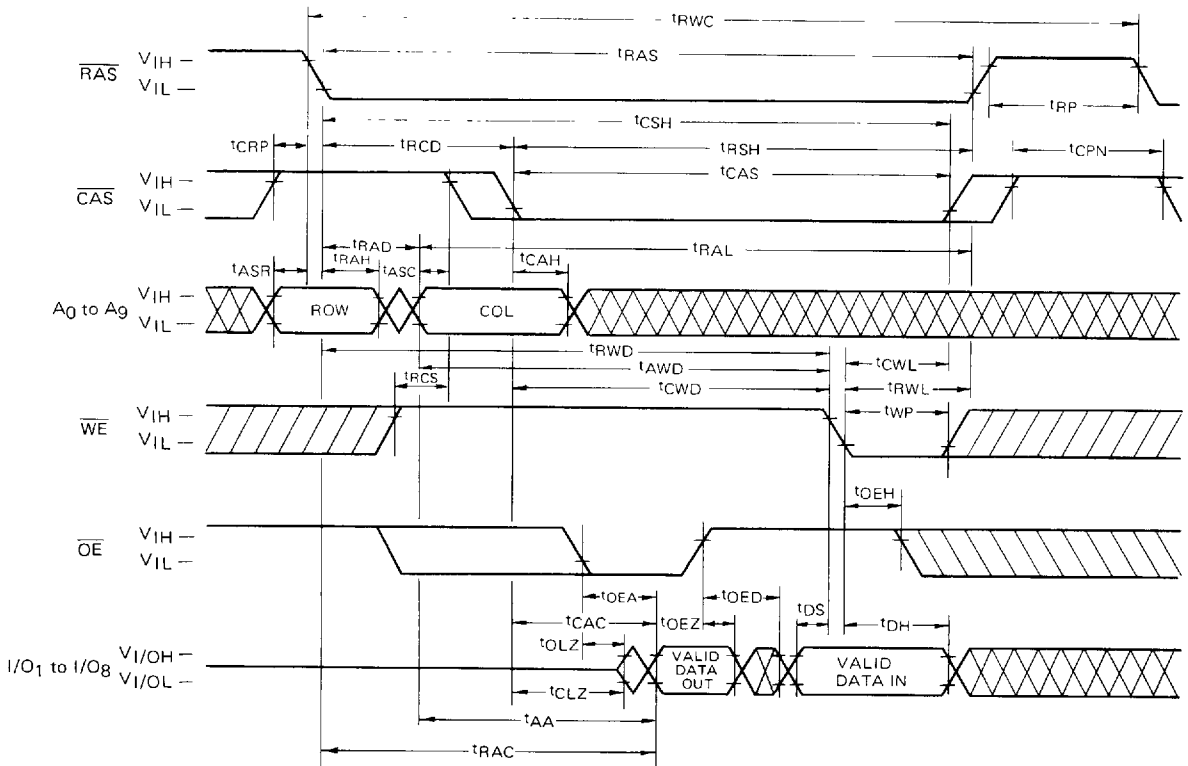


\*  $\overline{OE}$  Don't care

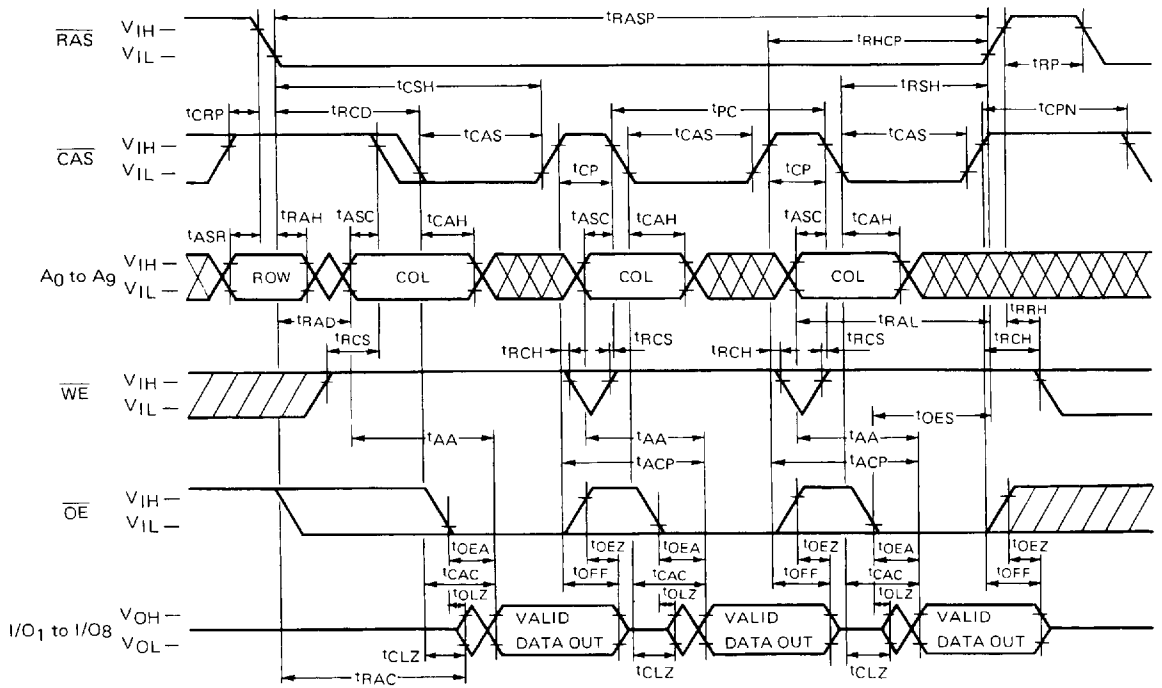
LATE WRITE CYCLE



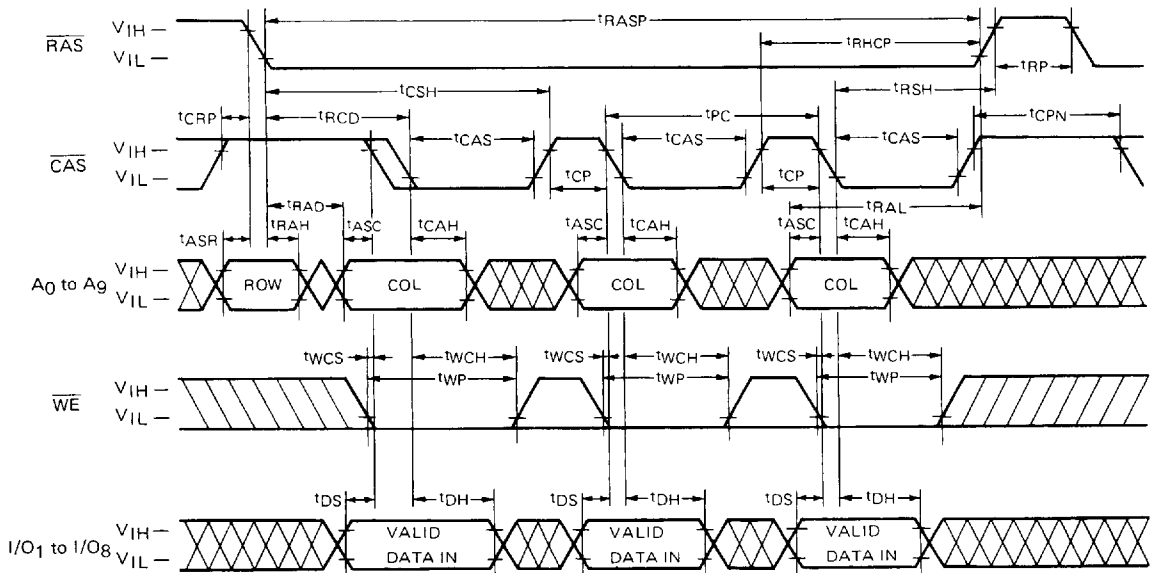
READ-MODIFY-WRITE CYCLE



PAGE MODE READ CYCLE



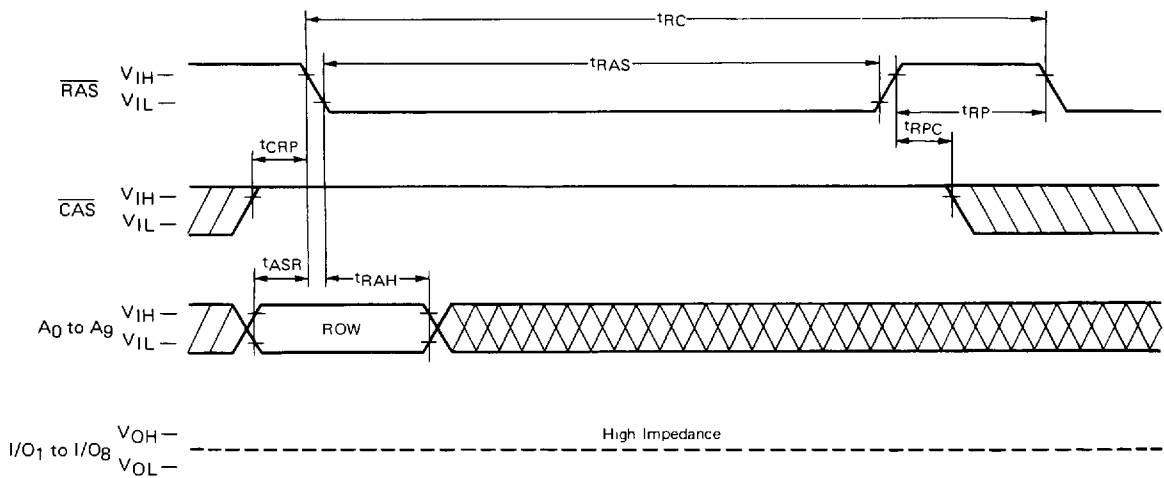
PAGE MODE EARLY WRITE CYCLE



\*  $\overline{OE}$  Don't care

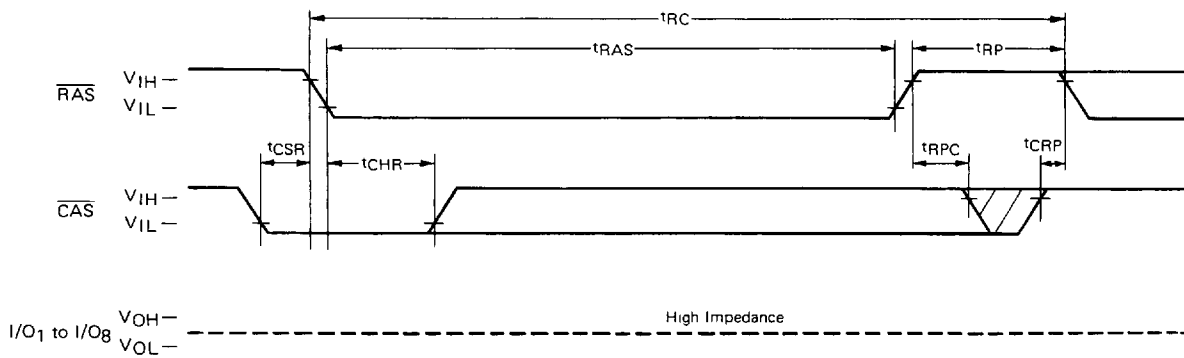


**RAS ONLY REFRESH CYCLE**



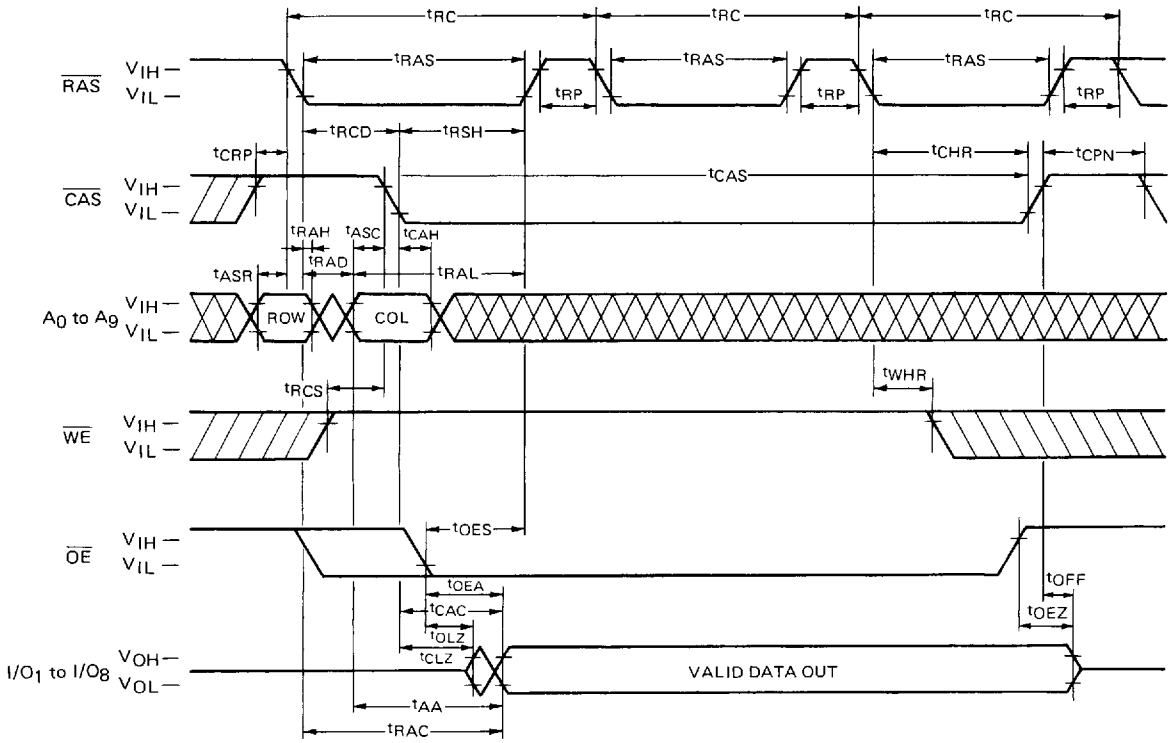
\*  $\overline{WE}$ ,  $\overline{OE}$ : Don't care

**CAS BEFORE RAS REFRESH**



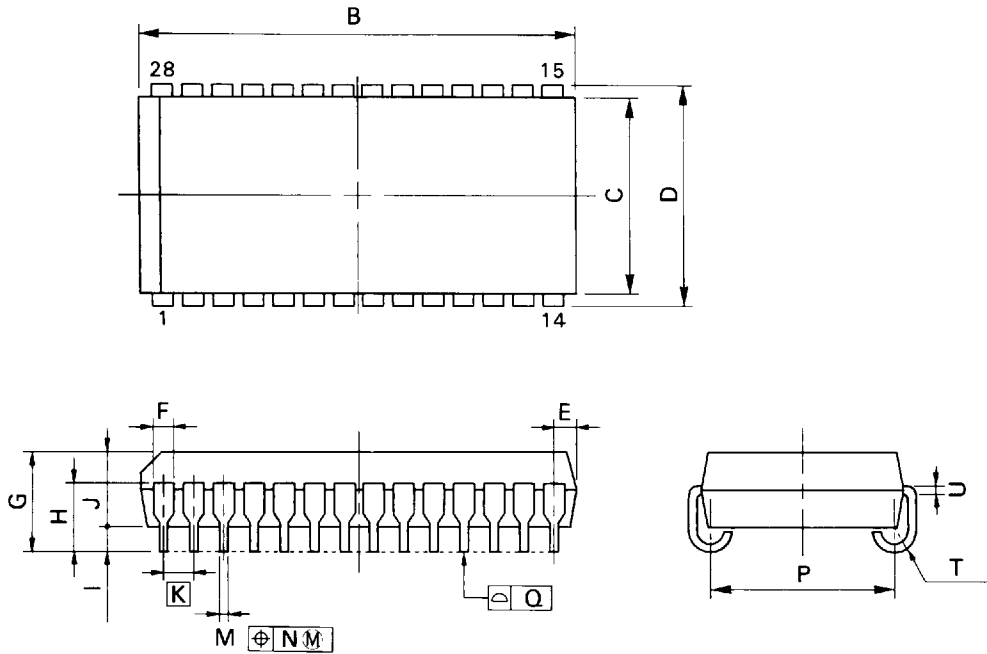
\*  $\overline{WE}$ ,  $\overline{OE}$ : Don't care

**$\overline{\text{CAS}}$  BEFORE  $\overline{\text{RAS}}$  HIDDEN REFRESH CYCLE**



PACKAGE INFORMATION\*

28PIN PLASTIC SOJ (400 mil)



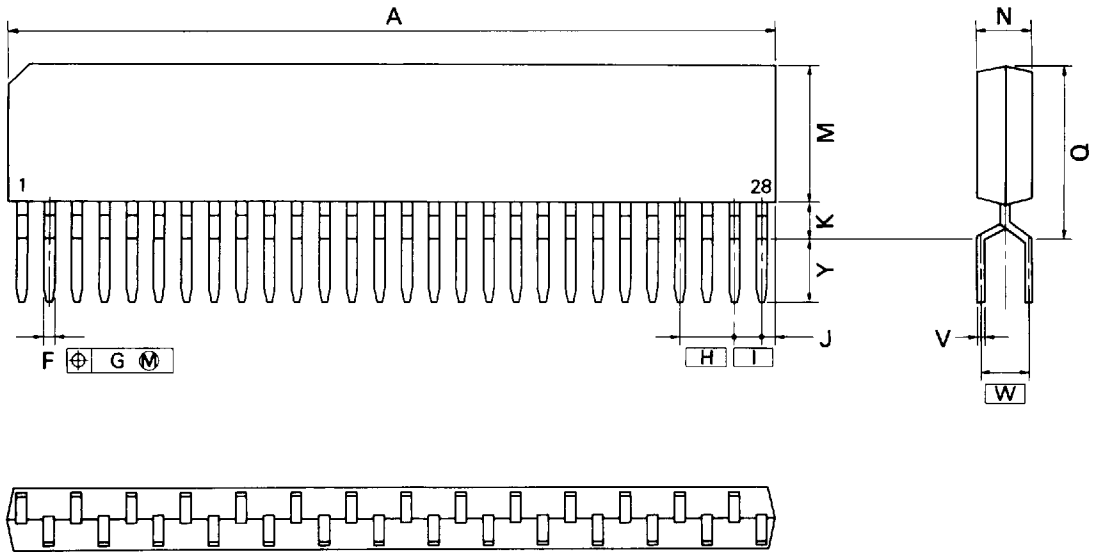
P28LA-400A-1

NOTE

Each lead centerline is located within 0.12 mm (0.005 inch) of its true position (T P) at maximum material condition.

ITEM	MILLIMETERS	INCHES
B	18.67 <sup>+0.2</sup> <sub>-0.35</sub>	0.735 <sup>+0.008</sup> <sub>-0.013</sub>
C	10.16	0.400
D	11.18 <sup>+0.2</sup>	0.440 <sup>+0.008</sup> <sub>-0.009</sub>
E	1.08 <sup>+0.15</sup>	0.043 <sup>+0.009</sup> <sub>-0.009</sub>
F	0.6	0.024
G	3.5 <sup>-0.2</sup>	0.138 <sup>+0.008</sup> <sub>-0.009</sub>
H	2.4 <sup>+0.2</sup>	0.094 <sup>+0.008</sup> <sub>-0.009</sub>
I	0.8 MIN	0.031 MIN
J	2.6	0.102
K	1.27 (T P)	0.050 (T P)
M	0.40 <sup>+0.10</sup>	0.016 <sup>+0.004</sup> <sub>-0.005</sub>
N	0.12	0.005
P	9.40 <sup>+0.20</sup>	0.370 <sup>+0.008</sup> <sub>-0.009</sub>
Q	0.15	0.006
T	R0.85	R0.033
U	0.20 <sup>+0.10</sup> <sub>-0.05</sub>	0.008 <sup>+0.004</sup> <sub>-0.002</sub>

28PIN PLASTIC ZIP (400mil)



P28V-254-400A

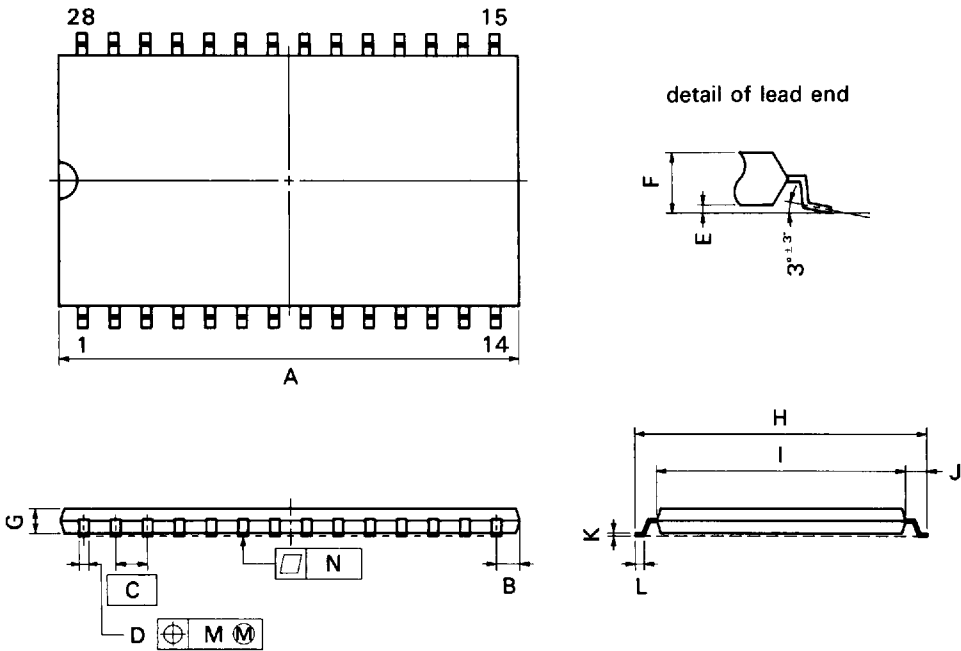
NOTE

Each lead centerline is located within 0.25 mm (0.010 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
A	36 83 MAX	1.450 MAX.
F	0.5 <sup>±0.1</sup>	0.020 <sup>+0.004</sup> <sub>-0.005</sub>
G	φ0.25	φ0.010
H	2 54	0.100
I	1.27	0.050
J	1.27 MAX.	0.050 MAX.
K	1.0 MIN	0.039 MIN.
M	8.9 MAX.	0.350 MAX.
N	2.8 <sup>±0.2</sup>	0.110 <sup>+0.008</sup> <sub>-0.008</sub>
Q	10 16 MAX	0.400 MAX.
V	0.25 <sup>+0.10</sup> <sub>-0.05</sub>	0.010 <sup>+0.004</sup> <sub>-0.003</sub>
W	2.54	0.100
Y	3.3 <sup>±0.5</sup>	0.130 <sup>±0.02</sup>



28 PIN PLASTIC TSOP (400mil)



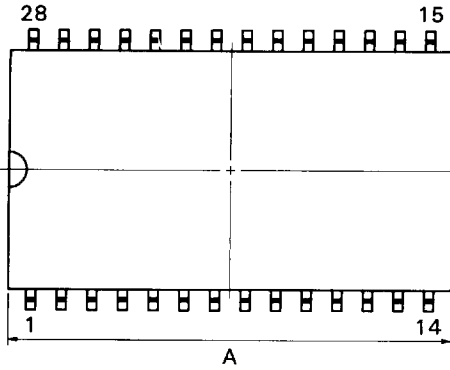
NOTE

Each lead centerline is located within 0.21 mm (0.009 inch) of its true position (T.P.) at maximum material condition.

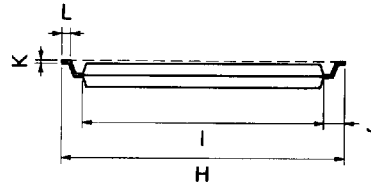
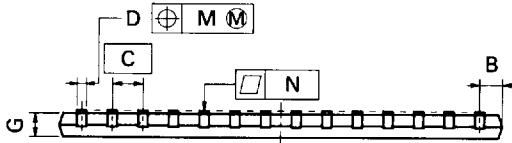
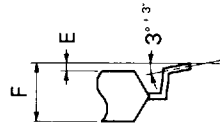
S28G5-50-7JD

ITEM	MILLIMETERS	INCHES
A	18.81 MAX.	0.741 MAX.
B	1.15 MAX.	0.046 MAX.
C	1.27 (T.P.)	0.050 (T.P.)
D	0.40 ± 0.10	0.016 <sup>+0.004</sup> / <sub>-0.006</sub>
E	0.05 ± 0.05	0.002 ± 0.002
F	1.1 MAX.	0.044 MAX.
G	0.97	0.038
H	11.76 ± 0.2	0.463 ± 0.008
I	10.16 ± 0.1	0.400 ± 0.004
J	0.8 ± 0.2	0.031 <sup>+0.008</sup> / <sub>-0.008</sub>
K	0.14 <sup>+0.10</sup> / <sub>-0.06</sub>	0.006 <sup>+0.004</sup> / <sub>-0.003</sub>
L	0.5 ± 0.1	0.020 <sup>+0.004</sup> / <sub>-0.006</sub>
M	0.21	0.009
N	0.10	0.004

28 PIN PLASTIC TSOP (400mil)



detail of lead end



S28G5-50-7KD

NOTE

Each lead centerline is located within 0.21 mm (0.009 inch) of its true position (T.P.) at maximum material condition.

ITEM	MILLIMETERS	INCHES
A	18.81 MAX.	0.741 MAX.
B	1.15 MAX	0.046 MAX.
C	1.27 (T.P.)	0.050 (T.P.)
D	0.40 <sup>+0.10</sup>	0.016 <sup>+0.004</sup>
E	0.05 <sup>+0.05</sup>	0.002 <sup>+0.002</sup>
F	1.1 MAX.	0.044 MAX.
G	0.97	0.038
H	11.76 <sup>±0.2</sup>	0.463 <sup>±0.008</sup>
I	10.16 <sup>±0.1</sup>	0.400 <sup>±0.004</sup>
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K	0.14 <sup>+0.10</sup>	0.006 <sup>+0.004</sup>
L	0.5 <sup>±0.1</sup>	0.020 <sup>+0.004</sup>
M	0.21	0.009
N	0.10	0.004

**RECOMMENDED SOLDERING CONDITIONS★**

The following conditions (see table below) must be met when soldering this product.

Please consult with our sales offices in case other soldering process is used, or in case soldering is done under different conditions.

**TYPES OF SURFACE MOUNT DEVICE**

For more details, refer to our document "SMT MANUAL" (IEI-1207).

μPD424800LE

Soldering process	Soldering conditions	Symbol
Infrared ray reflow	Peak package's surface temperature : 230° C or below, Reflow time : 30 seconds below (210° C or higher), Number of reflow process : 1, Exposure limit* : 7 days (10 hours pre-baking is required at 125° C afterwards).	IR30-107
VPS	Peak package's surface temperature : 215° C or below, Reflow time : 40 seconds below (200° C or higher), Number of reflow process : 1, Exposure limit* : 7 days (10 hours pre-baking is required at 125° C afterwards).	VP15-107
Partial heating method	Terminal temperature : 300° C or below, Flow time : 10 seconds or below, Exposure limit* : None	

\* : Exposure limit before soldering after dry-package is opened.  
Storage conditions : 25° C and relative humidity at 65% or less.

NOTE : Do not apply more than a single process at once, except for "Partial heating method".

μPD424800G5

Undecided: Please consult with our sales offices.

**TYPE OF THROUGH HOLE MOUNT DEVICE**

μPD424800V

Soldering process	Soldering conditions
Wave soldering	Solder temperature : 260° C or below, Flow time : 10 seconds or below.